

TECHNICAL DATA
DATASHEET D0413 REV.-

SILICON CARBIDE 1200 V / 40 mΩ POWER MOSFET DIE

Applications:

- Solar inverters • Switched-mode power supply • High voltage DC/DC converters
- Battery charges • Motor drives • Pulsed power application

Features:

- High blocking voltage with low on-resistance
- High speed switching with low capacitances
- Easy to parallel and simple to drive
- Avalanche ruggedness
- Resistant to latch-up
- Silver backside metal

Maximum Ratings ($T_A = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Characteristics	Symbol	Conditions	Min.	Typ.	Max.	Units	Note
Drain - Source Voltage	V_{DSmax}	$V_{GS} = 0\text{ V}$, $I_D = 100\text{ }\mu\text{A}$			1200	V	
Gate - Source Voltage (dynamic)	V_{GSmax}	AC ($f > 1\text{ Hz}$)	-8		+20	V	
Gate - Source Voltage (static)	V_{GSop}	Static		-4 / +18		V	[1]
Continuous Drain Current	I_D	$V_{GS} = 18\text{ V}$, $T_C = 25\text{ }^\circ\text{C}$			65	A	
		$V_{GS} = 18\text{ V}$, $T_C = 100\text{ }^\circ\text{C}$			46		
Pulsed Drain Current	$I_{D(pulse)}$	Pulse width t_P limited by T_{Jmax}			223	A	
Operating Junction and Storage Temperature	T_J , T_{stg}				-55 to 175	$^\circ\text{C}$	
Maximum Processing Temperature	T_{Proc}	10 min. maximum			325	$^\circ\text{C}$	

[1] Recommended turn off gate voltage is -4 V. Recommended turn on gate voltage is 18 V. Do not use with $V_{GSON} < 12\text{ V}$.

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Electrical Characteristics ($T_A = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Characteristics	Symbol	Conditions	Min.	Typ.	Max.	Units
Drain Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}$, $I_D = 100\text{ }\mu\text{A}$	1200			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 16\text{ mA}$	2	2.5	4	V
		$V_{DS} = V_{GS}$, $I_D = 16\text{ mA}$, $T_J = 175\text{ }^\circ\text{C}$		1.7		V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 1200\text{ V}$, $V_{GS} = 0\text{ V}$		1	100	μA
Gate Source Leakage Current	I_{GSS}	$V_{GS} = 18\text{ V}$, $V_{DS} = 0\text{ V}$		10	250	nA
Drain Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 18\text{ V}$, $I_D = 40\text{ A}$		40	52	m Ω
		$V_{GS} = 18\text{ V}$, $I_D = 40\text{ A}$, $T_J = 175\text{ }^\circ\text{C}$		50		m Ω
Transconductance	gfs	$V_{DS} = 20\text{ V}$, $I_{DS} = 40\text{ A}$		18		S
		$V_{DS} = 20\text{ V}$, $I_{DS} = 40\text{ A}$, $T_J = 175\text{ }^\circ\text{C}$		19		S
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{ V}$		2844		pF
Output Capacitance	C_{OSS}	$V_{DS} = 1000\text{ V}$		134		
Reverse Transfer Capacitance	C_{RSS}	$V_{AC} = 25\text{ mV}$		17		
C_{OSS} Stored Energy	E_{OSS}	$f = 1\text{ MHz}$		78		
Internal Gate Resistance	$R_{G(int)}$	$f = 1\text{ MHz}$, $AC = 25\text{ mV}$		1.3		Ω
Gate to Source Charge	Q_{gs}	$V_{DS} = 800\text{ V}$, $V_{GS} = -4 / 18\text{ V}$		66		nC
Gate to Drain Charge	Q_{gd}	$I_D = 40\text{ A}$		49		
Total Gate Charge	Q_g	Per IEC60747-8-4 pg 21		143		

* Pulse width < 200 μs .

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Reverse Diode Characteristics ($T_A = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Characteristics	Symbol	Conditions	Typ.	Max.	Units
Diode Forward Voltage	V_{SD}	$V_{GS} = -4\text{ V}, I_{SD} = 20\text{ A}$	4.3		V
	V_{SD}	$V_{GS} = -4\text{ V}, I_{SD} = 20\text{ A}, T_J = 175^\circ\text{C}$	3.6		V
Reverse Recovery Time	t_{rr}	$V_{GS} = -4\text{ V}, I_{SD} = 40\text{ A}, T_J = 25\text{ }^\circ\text{C}$	16		ns
Reverse Recovery Charge	Q_{rr}	$V_R = 800\text{V}$	221		nC
Peak Reverse Recovery Current	I_{mm}	$dif / dt = 3000\text{ A} / \mu\text{s}$	23		A

Typical Performance

All the graphs are based on a die placed in a TO-247-4 package.

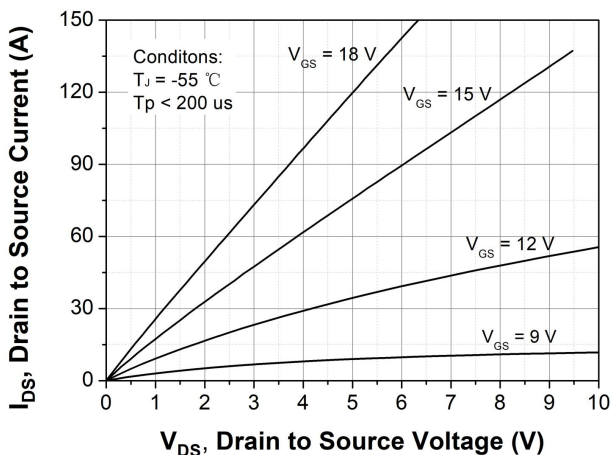


Figure 1. Output Characteristics $T_J = -55\text{ }^\circ\text{C}$

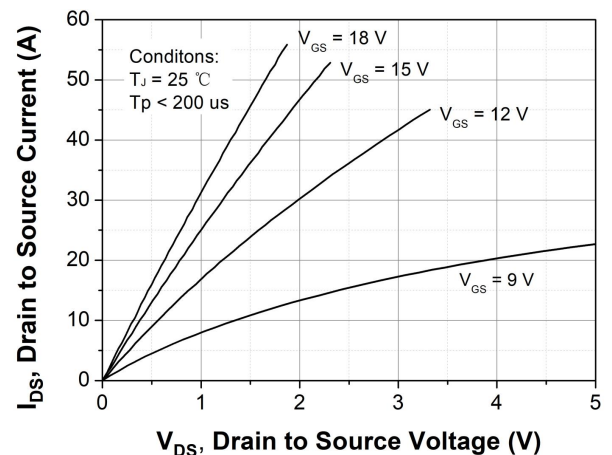


Figure 2. Output Characteristics $T_J = 25\text{ }^\circ\text{C}$

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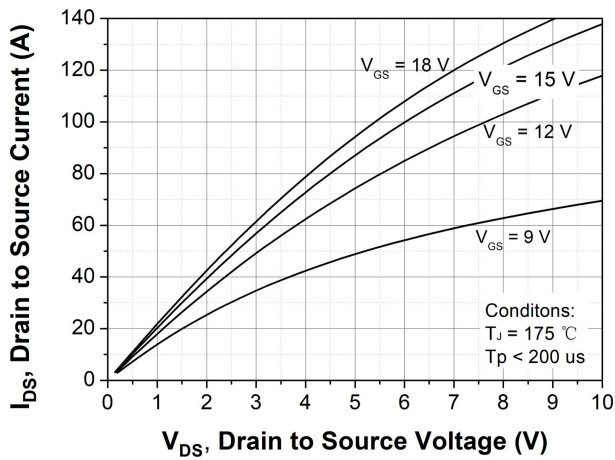


Figure 3. Output Characteristics $T_J = 175\text{ }^\circ\text{C}$

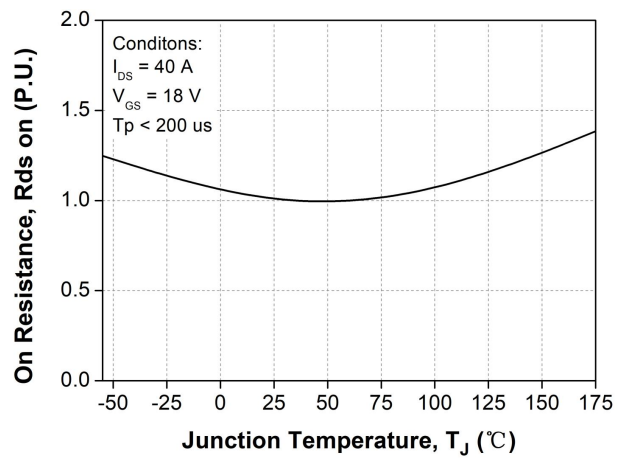


Figure 4. Normalized On-Resistance vs. Temperature

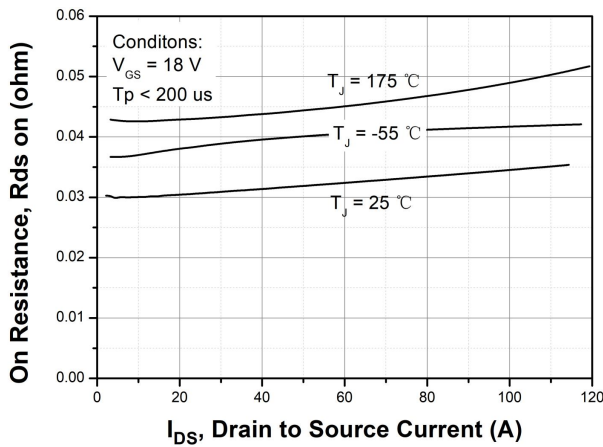


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

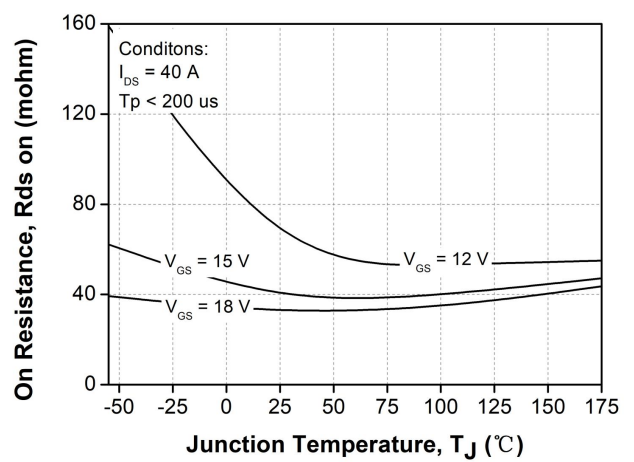


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

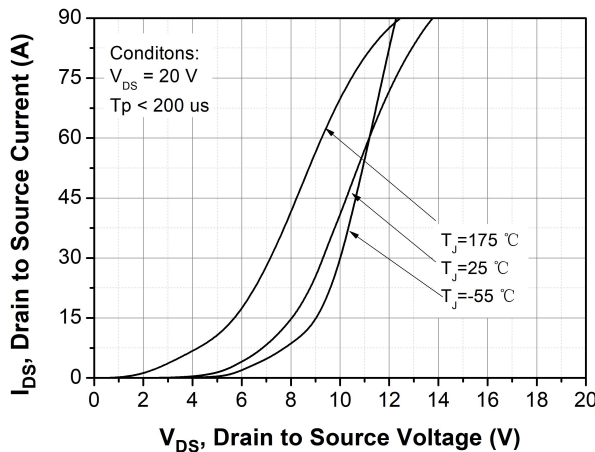


Figure 7. Transfer Characteristic for Various Junction Temperatures

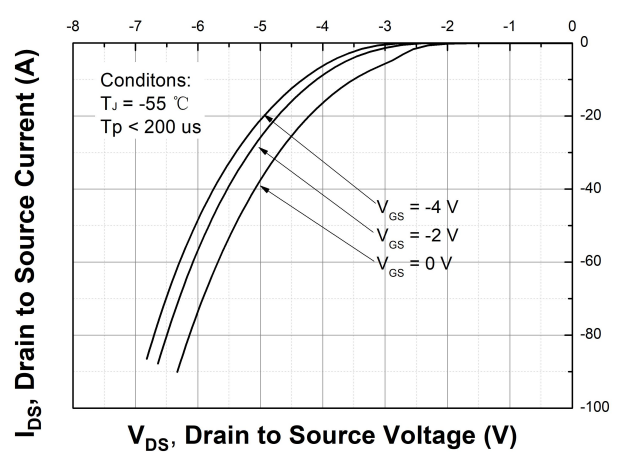


Figure 8. Body Diode Characteristic at $T_J = -55\text{ }^\circ\text{C}$

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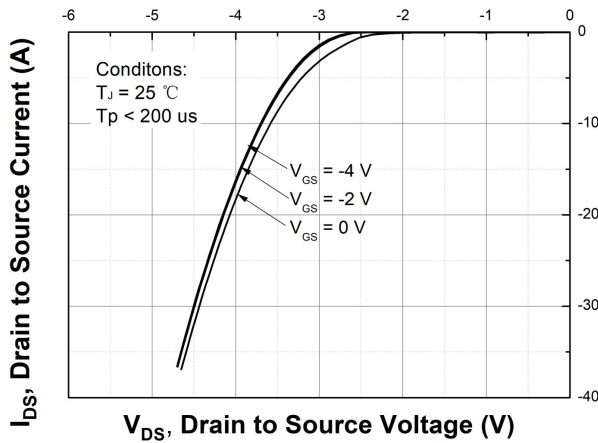


Figure 9. Body Diode Characteristic at $T_J = 25\text{ }^\circ\text{C}$

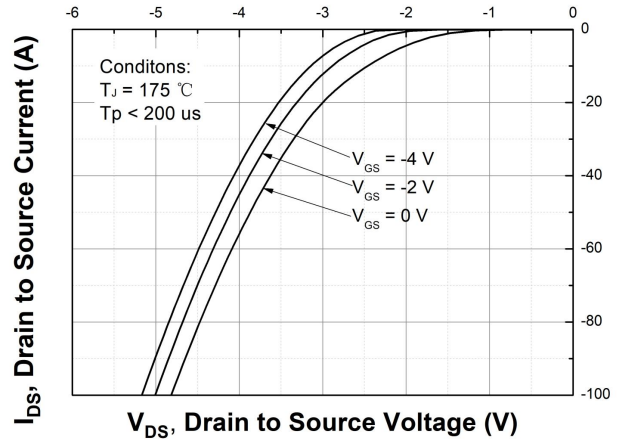


Figure 10. Body Diode Characteristic at $T_J = 175\text{ }^\circ\text{C}$

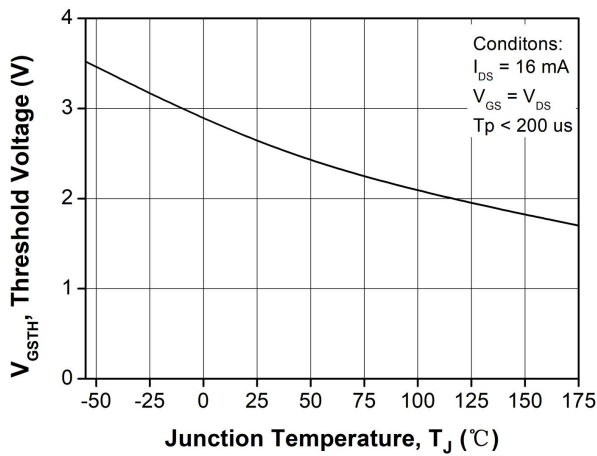


Figure 11. Threshold Voltage vs. Temperature

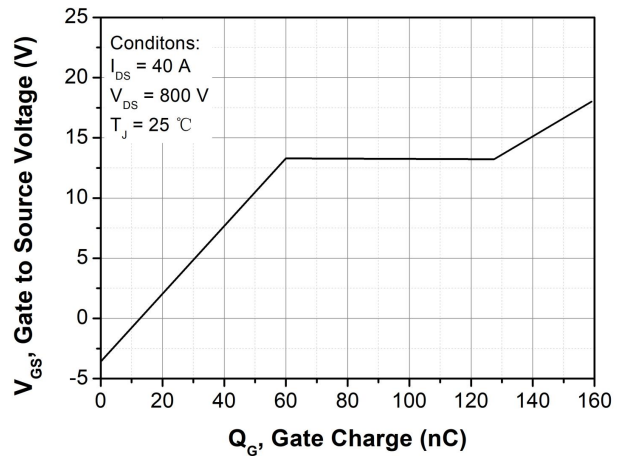


Figure 12. Gate Charge Characteristic

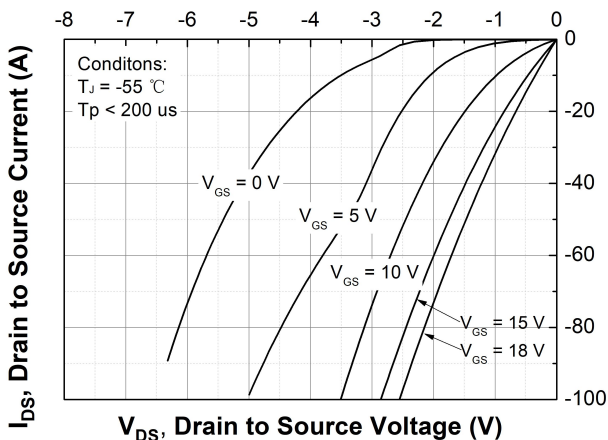


Figure 13. 3rd Quadrant Characteristic at $T_J = -55\text{ }^\circ\text{C}$

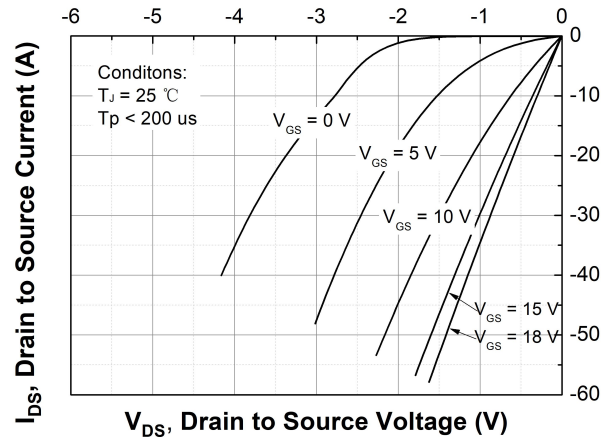


Figure 14. 3rd Quadrant Characteristic at $T_J = 25\text{ }^\circ\text{C}$

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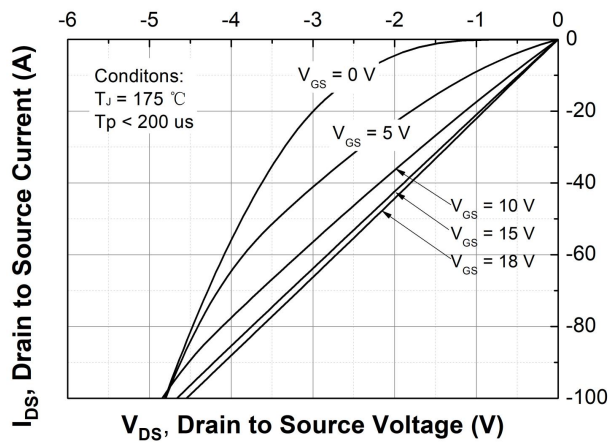


Figure 15. 3rd Quadrant Characteristic at $T_J = 175\text{ }^\circ\text{C}$

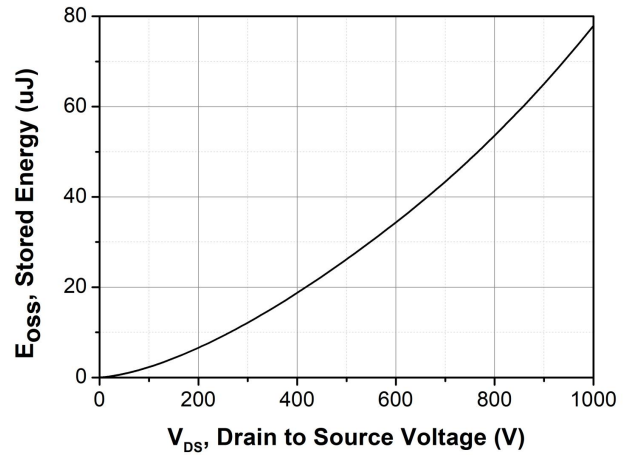


Figure 16. Output Capacitor Stored Energy

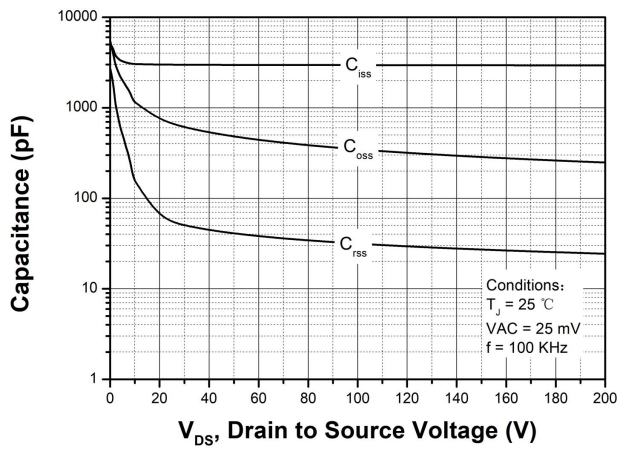


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200 V)

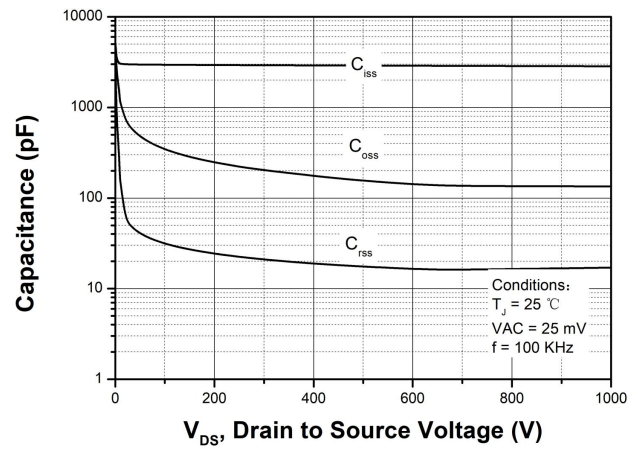
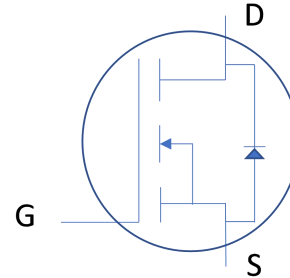
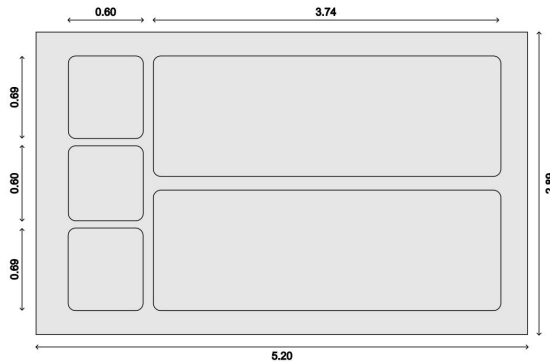


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1000 V)

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Mechanical Dimensions



Parameter	Typical Value	Unit
Die Dimensions (L x W)	Please contact your sales representative to get the detailed information about die layout and dimensions.	mm
Exposed Source Pad Metal Dimensions (L x W) Each		mm
Sense Pad Metal Dimensions (L x W)		mm
Gate Pad Dimensions (L x W)		mm
Top Side Source Metallization (Al)		μm
Top Side Gate Metallization (Al)		μm
Bottom Drain Metallization (Ni / Ag)		μm

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